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**In the United States Patent and Trademark Office**

Serial Number: 10/772,053  
Appn. Filed: 02/03/04  
Applicant: Guobiao Zhang  
Appn. Title: Three-Dimensional-Memory-Based Self-Test  
Integrated Circuits and Methods  
Examiner/GAU: Pham, Long/2814

Mailed: July 28, 2005

Commissioner of Patents and Trademarks  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In response to the Office Action mailed July 12, 2005, Applicant elects to have claims 1-12 and 18-20 examined. If there are any questions, Applicant can be contacted by email at [gzhang@3d-rom.net](mailto:gzhang@3d-rom.net).

Very respectfully,

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